## Fluence profiling at JSI TRIGA reactor irradiation facility 2

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#### Abstract 8

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We present an analysis of the fluence profile at the JSI TRIGA neutron reactor facility in Ljubljana. For the study, multi-pad Low-Gain Avalanche Diodes (LGADs) are used. The deactivation of acceptor doping in the gain layer implant due to the irradiation, typical of LGAD devices, is exploited to map the fluence profile inside the irradiation channels. The amount of active doping of the LGAD gain layer is extracted via capacitance-voltage measurements for each pad before and after irradiation to a fluence of  $1.5 \times 10^{15} \, n_{eg}/cm^2$ , where  $n_{eq}$  stands for 1 MeV equivalent neutron count, providing a precise and prompt measurement of the fluence distribution over the LGAD sensor. Experimental results are compared to neutron fluence expectations calculated with Monte Carlo techniques.

Keywords: TRIGA reactor, LGAD, irradiation facility, fluence profile 9

#### 1. Introduction 10

The TRIGA Mark II reactor at the Jožef Stefan Institut (JSI) [1] is 11 extensively used by the High Energy Physics community to study and test 12 radiation damage effects on detector materials and read-out electronics [2]. 13

Recently, the increasing sensitivity of silicon devices to the effects of ra-14 diation triggered the discussion on the fluence spread that can affect irradia-15 tion campaigns. In particular, performance variation of Low-Gain Avalanche 16 Diodes (LGADs) after irradiation [3] suggested the possibility to precisely 17 map the fluence profile at the JSI facility. 18

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LGADs are n-in-p silicon sensors with a highly p-doped region close to 19 the n-electrode, called gain implant, to create a local enhancement of the 20 electric field responsible for the charge carrier multiplication [4]. It has been 21 observed that the Boron dopants in the gain layer get deactivated by the 22 radiation. This effect is known as acceptor removal [5] and has been precisely 23 characterised and tested [6], opening the possibility to use LGADs as devices 24 suitable to measure the fluence variation inside the irradiation channels of 25 the JSI facility. 26

LGAD sensors have been used with a straightforward procedure and have proven to be an effective tool to build a fluence profile map inside the reactor core.

### 30 2. The Experimental Method

The idea behind the present measurement is to use LGAD arrays of pixels to precisely quantify the different neutron fluence experienced by each pixel. For this purpose, sensors from wafer 1 of the FBK USFD3 production batch [7] have been used, made of an array of  $5 \times 5$  pixels. A drawing of the sensors is shown in Figure 1: the area of each pixel is  $1.3 \text{ mm} \times 1.3 \text{ mm}$ , and the total sensor area is  $7.7 \text{ mm} \times 7.7 \text{ mm}$ .

The study exploits the deactivation of the gain implant dopants by particle radiation known as acceptor removal and parametrised as

$$N_A(\Phi) = N_A(0) \cdot e^{-c \cdot \Phi} \tag{1}$$



Figure 1: Schematic draw of the FBK sensors used for the study.

<sup>39</sup> where  $N_A(0)$   $(N_A(\Phi))$  is the effective acceptor density of the gain layer before <sup>40</sup> irradiation (after a fluence  $\Phi$ ), and *c* is the removal coefficient, depending on <sup>41</sup> the initial doping and on the gain layer design. The *c* coefficient has been <sup>42</sup> extensively measured through several campaigns [6, 8].

The determination of the active acceptor concentration is performed through capacitance-voltage (C-V) measurements. The value of the bias voltage at which the gain layer is depleted corresponds to a drop in the measured capacitance, defined as a knee (see Fig. 2) and indicated as  $V_{GL}$ .

In particular, for each pad, the  $V_{GL}$  has been defined as the point at which 47 the capacitance reaches a fixed value in the proximity of the knee, assuming 48 that for a fixed pad geometry, an equal value of capacitance represents the 49 identical amount of depleted volume, making the measurement extremely 50 sensitive to the changes in active doping. Such capacitance value has been 51 chosen to be 150 pF for both un-irradiated and irradiated sensors. It is worth 52 noting that the method has been proven to be equivalent to other methods 53 used to extract  $V_{GL}$ , e.g. in [6]. Furthermore, it guarantees a prompt and 54 easy tool to access a precise estimate of the active doping at a given depth 55 inside the pad under test. 56

To eliminate the effects of non-uniformities of gain layer doping implantation and systematic uncertainties on the gain layer depletion measurement, the ratio of  $V_{GL}$  before and after irradiation will be considered. Therefore, from the variation of

$$\frac{V_{GL}(\Phi)}{V_{GL}(0)} = e^{-c \cdot \Phi},\tag{2}$$

and assuming a constant c, which is a valid assumption considering an initial



Figure 2: The C-V characteristics from all the 25 pads of the 16-6 sensor before (left) and after irradiation to a fluence of  $1.5 \times 10^{15} \,\mathrm{n_{eq}/cm^2}$  (right). The horizontal dotted lines correspond to the value of  $C = 150 \,\mathrm{pF}$ , and the vertical bands highlight the corresponding values of reverse bias. The capacitance of full depletion of the pads under test is  $C_{FD} \sim 3.2$ .

doping variation of less than 2 % [9], the measured variation of the ratio
 directly quantifies a variation in the received fluence.

For the present study, 8 LGAD sensors have been irradiated to a fluence of  $1.5 \times 10^{15} n_{eq}/cm^2$  by using the channel F19 of the JSI reactor [10]. This channel is the one mainly used to irradiate samples for high-energy physics detector developments. The irradiation has been done at full reactor power of 250 kW. At such power, the target fluence in channel F19 is reached in 926 seconds.

## 70 3. The Experimental Setup

For irradiation at the JSI facility, cylindrical plastic containers with a diameter of about 2 cm and a height of about 10 cm are used. By placing the LGAD sensors in a fixed position inside a container, it is possible to investigate and map the geometrical variation of the neutron flux inside the irradiation volume.

Eight sensors have been fixed on plastic support and placed at two different depths inside the container. The support consists of four arms placed orthogonally to each other, and four sensors have been attached at the same depth on each arm of the plastic strut, as shown in Fig. 3.



Figure 3: The placement of the 8 LGAD sensors inside the irradiation container is shown: 4 sensors are placed at two different depths, fixed on a plastic support. The sensor numbering and distance from the container bottom are reported.

The pad-by-pad C-V characterisation before and after irradiation has 80 been performed at room temperature, connecting a Keysight B1505A Power 81 Device Analyzer to the probe station. A high voltage source-monitor unit 82 was used together with a multi-frequency capacitance measurement unit, 83 interfaced via a bias-T and referred to a common ground value. The frequency 84 of the AC signal was set to 1 kHz, with an amplitude of 50 mV, and a parallel 85 capacitor-resistor model was used to extract the capacitance value. The chuck 86 of the probe station was negatively biased, and one needle at zero voltage 87 moved over the 25 pads of each sensor. One additional needle set at zero 88 voltage has been used to ground the guard ring of the sensor in order to 89 collect dark current from the sensor periphery and reduce the noise on the 90 capacitance measurement. 91

#### <sup>92</sup> 4. The Measurement Technique

For all the  $1.3 \text{ mm} \times 1.3 \text{ mm}$  measured pads,  $V_{GL}$  has been extracted as the voltage value at which the capacitance reaches 150 pF. As the reverse voltage was provided to the sensor in steps of 0.2 V, to estimate the gain layer depletion voltage, a linear fit to the two capacitance measurements immediately lower  $(C_{low})$  and higher  $(C_{high})$  than 150 pF has been performed, according to

$$V_{GL} = V_{low} + \frac{V_{high} - V_{low}}{C_{high} - C_{low}} \cdot (150 \,\mathrm{pF} - C_{low}),\tag{3}$$

<sup>99</sup> being  $V_{low}$  and  $V_{high}$  the measured voltage values preceding and following the <sup>100</sup>  $V_{GL}$  point, respectively. The linear fit represents a good approximation of <sup>101</sup> the evolution of the C-V characteristics, given the small interval used in the <sup>102</sup> voltage measurement.

The  $V_{GL}$  values extracted for the sensor 16-6 before and after irradiation to a fluence of  $1.3 \times 10^{15} \,\mathrm{n_{eq}/cm^2}$  are shown in Fig. 4. Prior to irradiation, it is possible to observe the non-uniformity in the dopant implantation on the gain layer; for the sensor under test, the spread in concentration is measured to be < 0.9 %. After the irradiation, a modification in the geometrical trend of  $V_{GL}$  non-uniformity become visible, with an increase of its relative spread to about 2 %.

As explained in Sect. 2, for our analysis we will consider the ratio of  $V_{GL}$  before and after irradiation, to remove the effect of initial doping nonuniformities and the sistematics affecting the measurement technique. Figure 5 shows the resulting ratio for the sensor 16-6: it is possible to observe



Figure 4: The extracted values of  $V_{GL}$  for the sensor 16-6 before (top) and after (bottom) irradiation to a fluence of  $1.5 \times 10^{15} \,\mathrm{n_{eq}/cm^2}$ , reported as a function of the column number (left) and of the row number (right). The distance between the centre of the neighbouring pads and, therefore, the distance between each measured point is 1.3 mm.

as irradiation introduces a strong horizontal non-uniformity, while there isno obvious trend as a function of the vertical direction.



Figure 5: The ratio of the  $V_{GL}$  values before and after irradiation for the sensor 16-6 is reported as a function of the column number (left) and the row number (right). The distance between the centre of the neighbouring pads and, therefore, the distance between each measured point is 1.3 mm.

As a systematic check, results have been reproduced considering fixed 116 capacitance values of 160 pF and 140 pF. The resulting values of  $V_{GL}$  ratios 117 before and after irradiation are modified by less than 0.1% in the first case, 118 while a maximum spread of -1.2% to 0.6% has been observed in the latter 119 case. This difference might be explained by the fact that for  $C = 140 \,\mathrm{pF}$ 120 in irradiated sensors, the curve approaches a kink in the measurement, see 121 Fig 2 (right): such kink can be due to the reach of a not optimised frequency 122 value used in the measurement process when the depleted volume as a func-123 tion of the applied bias moves from the gain implant to the sensor bulk 124 region. Therefore, a systematic uncertainty of 0.9% is attributed to all the 125 measured values of the  $V_{GL}$  ratio. 126

Also, the results of the fixed capacitance method have been compared 127 with the method that considers the cusp in the parallel resistance as a func-128 tion of the bias  $(V_{GL}^R \text{ in } [6])$ . The difference in the results between the two 129 methods has been measured to be of 1.4%. However, it is important to note 130 that the  $V_{GL}^R$  method guarantees a minor precision at the fluence under test, 131 as at relatively high fluences, the cusp enlarges, resulting in higher uncer-132 tainty in determining the exact position of its maximum. Thus, the method 133 of the fixed capacitance provides a more precise estimate of  $V_{GL}$  and the rel-134 ative difference between the two methods is not considered as an uncertainty 135 of the presented results. . 136

#### 137 5. The Simulation

The experiment was reproduced by Monte Carlo particle transport simulations using the MCNP v.6.1 [11] code with ENDF/B-VII.0 nuclear data libraries [12]. Computations were performed in criticality mode, and results were normalised to full reactor power (250 kW) [13].

A detailed JSI TRIGA reactor model was used, with core configuration 142 and control rod positions resembling the configuration used during the exper-143 iment, displayed in Fig. 6 (right). Initial simulations were performed without 144 the sensor assembly in the F19 irradiating channel in order to assess the 145 homogeneity and possible gradients of the fast neutron flux component (neu-146 trons with energy  $E_n > 100 \text{ keV}$ ) within the irradiation position. The neutron 147 flux was calculated on a mesh superimposed over F19 irradiation position 148 with resolution of  $2 \,\mathrm{mm} \times 2 \,\mathrm{mm} \times 2 \,\mathrm{mm}$ . Neutron and gamma fluxes were 149 tallied in three distinct energy groups, as denoted in Table 1. The fast neu-150 tron flux distribution and its gradients in the x and y directions are displayed 151



Figure 6: Two distinct orientations of the sensors inside the irradiation channel (left) and a detailed view of the JSI TRIGA MCNP computational model (right).

<sup>152</sup> in Fig. 7. One can observe the increase of the fast neutron flux component <sup>153</sup> in close proximity to the neighbouring fuel elements.

In the second stage, sensors and the carrier board constituting a cross configuration (see Fig. 3), as well as the polyethylene container, were also modelled in detail and inserted into the irradiation channel into the F19 position, shown in Fig. 6 (right). The sensor support was modelled as the FR4 base plate of 1 mm thickness, while the sensors themselves were modelled as boxes of pure silicon with a size of  $7.7 \text{ mm} \times 7.7 \text{ mm} \times 0.63 \text{ mm}$ . Kapton tape with a thickness of 0.05 mm covering the entire assembly was also modelled.

	Neutron		Gamma	
	Lower E	Upper E	Lower E	Upper E
1	$0\mathrm{eV}$	$0.625\mathrm{eV}$	$0\mathrm{eV}$	$100\mathrm{keV}$
2	$0.625\mathrm{eV}$	$100\mathrm{keV}$	$100\mathrm{keV}$	$1{ m MeV}$
3	$100\mathrm{keV}$	$100{ m MeV}$	$1{ m MeV}$	$100{\rm MeV}$

Table 1: Lower and upper energy (E) bounds of tallied neutrons and gamma rays.



Figure 7: Fast neutron  $(E_n > 100 \text{ keV})$  flux distribution in X-Y direction and their gradients in X and Y direction inside the F19 irradiation channel, at Z-levels corresponding to the mid-depth levels of the inserted sensor assembly. The white dotted line denotes the irradiation channel aluminium walls, while the arrow points to the core centre.

The sensor assembly model is schematically displayed in Fig. 8. The iso-161 topic composition of the above-mentioned materials was obtained using the 162 MATSSF code [14] and is reported in Appendix A. Due to the unknown axial 163 orientation during the experiment, two distinct orientations were modelled: 164 with the carrier board cross arms perpendicular to the reactor core centre and 165 with arms diagonal with respect to the core centre, Fig. 6 (left). The same 166 energy group structure was used for tallying neutron and gamma flux in each 167 individual LGAD sensor, as well as on a mesh superimposed over the entire 168 irradiated container with a resolution of  $2 \text{ mm} \times 2 \text{ mm} \times 2 \text{ mm}$ , displayed in 169



Figure 8: The model of the LGAD sensor's assembly on FR4 supports, covered with Kapton tape.

Fig. 9, along with numbering of LGAD sensor used in the simulations. The 170 fast neutron flux difference between the empty irradiation channel and with 171 inserted polyethylene container and sensor sample is displayed in Fig. 10. By 172 comparing with simulated flux values shown in Fig. 7, it is possible to ap-173 preciate that the insertion of samples changes the neutron flux of the empty 174 irradiation channel by up to ~ 10 %. Fast neutron flux  $(E_n > 100 \,\text{keV})$  av-175 eraged over individual sensor are provided in Table 2. Moreover, each sensor 176 was divided into  $(5 \times 5)$  sections, corresponding to positions of individual 177 pixels (Figure 1) in order to asses the fast neutron flux variation, sensed by 178 each sensor. 179



Figure 9: Fast neutron ( $E_n > 100 \text{ keV}$ ) flux field in irradiation position F19 at full reactor power (250 kW) for two sample orientations. Visualisations at the z-axis and sensor mid-planes. Relative statistical uncertainty < 1%. Numbers denote the sensor numbering convention used in calculations, and the arrow indicates the direction towards the reactor core centre. White lines denote the edge of the irradiation channel (dashed), polyethylene container and the PCB with the sensors.



Figure 10: Fast neutron  $(E_n > 100 \text{ keV})$  flux field difference in irradiation position F19 at full reactor power (250 kW) between empty irradiation channel and with inserted polyethylene container and sample at two orientations. Visualisations at the z-axis and sensor midplanes. Relative statistical uncertainty between 10 % to 30 %. Numbers denote the sensor numbering convention used in calculations, and the arrow indicates the direction towards the reactor core centre. Lines in the figure denote the edge of the irradiation channel (dashed), polyethylene container and the PCB with the sensors.

Table 2: Fast neutron flux ( $E_n > 100 \text{ keV}$ ) at reactor power of 250 kW. Mean values per sensor and the variation over individual pixels. Mean value of the statistical uncertainty spans from 0.62% to 0.82%, while statistical uncertainties on the mesh span from 2.2% to 2.7%.

No	Diagonal		Perpendicular	
INO.	Mean	Variation [%]	Mean	Variation [%]
	$[cm^{-2}s^{-1}]$		$[cm^{-2}s^{-1}]$	
1	$1.684 \times 10^{12}$	$+5.1 \\ -4.8$	$1.510\times10^{12}$	$+7.3 \\ -6.8$
2	$1.741\times10^{12}$	$+5.5 \\ -4.7$	$1.577\times10^{12}$	$+4.2 \\ -5.1$
3	$1.741 \times 10^{12}$	$+5.4 \\ -4.2$	$1.596 \times 10^{12}$	$+4.0 \\ -5.1$
4	$1.773 \times 10^{12}$	$+4.8 \\ -4.0$	$1.633 \times 10^{12}$	$+4.7 \\ -3.5$
5	$1.556 \times 10^{12}$	$+6.1 \\ -6.2$	$1.742\times10^{12}$	+5.6 -10.2
6	$1.647 \times 10^{12}$	+5.8 -5.6	$1.787 \times 10^{12}$	$+6.1 \\ -6.1$
7	$1.531 \times 10^{12}$	$+6.4 \\ -6.1$	$1.648 \times 10^{12}$	$+2.7 \\ -2.3$
8	$1.607 \times 10^{12}$	$+6.9 \\ -5.9$	$1.698\times10^{12}$	$+4.8 \\ -3.5$

#### 180 6. The Results

The ratios of the  $V_{GL}$  before and after irradiation are shown for each 181 pixel as a function of the column number for the eight sensors under test, split 182 between the top (Fig. 11) and the bottom (Fig. 12) part of the container. For 183 both the top and the bottom positioning, there is one sensor with a high value 184 of the  $V_{GL}$  ratio, above 0.62 (19-6 and 22-5, respectively), one with a low ratio 185 value, below 0.56 (namely, 16-5 and 22-6), and there are two sensors with a 186 medium ratio, of about 0.58 (22-3 and 16-6 in the top part, 13-5 and 16-4 187 in the bottom part). The orientation of the container during the irradiation 188 inside the F19 channel is unknown. Still, the observed trend in the received 189 fluence is compatible with the gradients shown by the simulation relative to 190 the sensors oriented perpendicularly to the centre of the reactor core, as in 191 Fig. 9 (right). The results suggest that, during the irradiation, the sensors 19-192 6 and 22-5 were closer to the reactor core centre, while sensors 16-5 and 22-6 193 were farther away. Moreover, column 1 of each sensor points to the centre 194 of the cross support. Therefore, the opposite trend of the ratios for, e.g., 195 sensors 22-5 and 22-6 indicate that in 22-5, the pixels in column 5 are more 196 exposed to irradiation, while for 22-6, pixels in column 1 experienced higher 197 irradiation, in agreement with the geometrical construction of the setup. 198



Figure 11: The ratio of the  $V_{GL}$  values before and after irradiation for the four sensors placed in the top part of the canister. The distance between each measured point is 1.3 mm.



Figure 12: The ratio of the  $V_{GL}$  values before and after irradiation for the four sensors placed in the bottom part of the canister. The distance between each measured point is 1.3 mm. 13

Furthermore, it has been measured that the vertical spread of the fluence 199 is mild, as it is visible from two sensors placed on the same arm of the 200 holder structure, namely, 22-5 in the bottom part and 19-6 in the top one, 201 as shown in Fig. 13. A linear interpolation of the measured  $V_{GL}$  ratios on all 202 the pixels from the column 1 of the sensors 22-5 and 19-6 is displayed: the 203 variation of the ratio values spanning over a vertical distance of 59.2 mm is 204 quantified by the angular coefficient as a parameter of the fit, measured to 205 be  $5.05 \times 10^{-5} \,\mathrm{mm^{-1}}$ . Also, the relative difference between the lowest row 206 of the sensor 22-5 (row 5) and the highest row of the sensor 19-6 (row 1) is 207 0.8% for column 1 and rises to 1.1% in column 5. This observation agrees 208 with the simulation, as in Figg. 9 and 10. 209



Figure 13: The ratio of the  $V_{GL}$  values before and after irradiation two sensors placed on the same arm of the plastic structure.

The conversion between the measured ratios of  $V_{GL}$ , reflecting the frac-210 tion of active gain implant that survived the irradiation as presented in 211 Eq.(1), to the value of fluence experienced by each pixel make use of the 212 formula in Eq.(2) and uses as value for the acceptor removal coefficient 213  $c = 3.85 \times 10^{-16} \,\mathrm{cm}^2$ , extracted from previous measurements on sensors from 214 the same production batch [15]. The uncertainty on the c factor is 12 % and 215 accounts for the different methods used to extract  $V_{GL}$  at various fluences 216 and from the uncertainty on those fluences, which represent the highest con-217 tribution to the uncertainty. 218



Figure 14: Average fluence seen by the eight sensors under test. The overall average is also shown (black circle).

Figure 14 reports the fluence experienced by each tested sensor, averaged over all 25 pixels. The evolution of Eq.(2) for the FBK wafer from which the tested sensors are taken (W1 UFSD3) is superimposed to the data points to

Table 3: Average, minimum and maximum fluence ( $\Phi$ ) experienced by each of the eight measured sensors. Fluence values are expressed in units of  $10^{15} \, n_{eq}/cm^2$ . Relative variations of the fluences measured by each sensor with respect to the average fluence of  $1.37 \times 10^{15} \, n_{eq}/cm^2$  is reported.

Sensor No.	Average $\Phi$	$\Phi$ Min	$\Phi$ Max	Variation [%]
19-6	1.22	1.18	1.26	$-11.2^{-8.6}_{-13.8}$
22-3	1.35	1.30	1.38	$-1.7^{+0.8}_{-5.3}$
16-5	1.50	1.46	1.53	$+9.1^{+11.3}_{+6.6}$
16-6	1.35	1.33	1.37	$-1.9^{-0.4}_{-3.5}$
22-5	1.21	1.17	1.23	$-12.1^{-10.1}_{-14.7}$
13-5	1.40	1.36	1.43	$+ 1.9^{+4.2}_{-0.8}$
22-6	1.55	1.52	1.58	$+ 13.1^{+15.4}_{+10.7}$
16-4	1.41	1.37	1.44	$+ 2.7^{+4.6}_{-0.1}$

highlight the evolution of the  $V_{GL}$  ratio with the fluence. The average fluence experienced by all the 8×25 measured pixels is  $\Phi_{ave} = 1.37 \times 10^{15} \,\mathrm{n_{eq}/cm^2}$ ,  $0.13 \times 10^{15} \,\mathrm{n_{eq}/cm^2}$  lower than the expected value of  $1.5 \times 10^{15} \,\mathrm{n_{eq}/cm^2}$ .

The average fluences seen by each sensor are reported in Table 3, together 225 with the minimum and maximum fluence experienced by the pixels in each 226 of the eight measured sensors. The relative variations are also reported, ob-227 tained by comparing the average sensor values with the overall average value 228 equal to  $1.37 \times 10^{15} \, n_{ea}/cm^2$ . Considering minimum and maximum values of 229 fluence experienced by the pixel, the fluence variation ranges from -14.7%230 to 15.4%, observed on the sensors placed on the bottom part of the con-231 tainer. The variation in the top region spans between -13.7% to 11.4%. 232

<sup>233</sup> Concerning the vertical variation of the fluence, it has been observed a <sup>234</sup> minimum difference of  $2.13 \times 10^{13} n_{eq}/cm^2$  between sensors 19-6 and 22-5 and <sup>235</sup> a maximum difference of  $7.81 \times 10^{13} n_{eq}/cm^2$  between sensors 16-5 and 22-6. <sup>236</sup> Figures 15 and 16 compare the results from the data with the simulation <sup>237</sup> obtained considering a perpendicular or a diagonal orientation of the sensors



Figure 15: Comparison of the average fluence measured by the sensors and the simulated fluence for sensors oriented perpendicularly to the reactor core centre. Error bars represent the minimum and maximum fluence measured by the pixels in each sensor. The error on the factor is not added to the data. Reactor power has been set to  $250 \,\text{kW}$  for  $926 \,\text{s}$ .



Figure 16: Comparison of the average fluence measured by the sensors and the simulated fluence for sensors oriented diagonally to the reactor core centre. Error bars represent the minimum and maximum fluence measured by the pixels in each sensor. The error on the c factor is not reported on the data. Reactor power has been set to  $250 \,\text{kW}$  for  $926 \,\text{s}$ .

under test to the core reactor centre, respectively, as reported in Tables 2 and 3. The 12 % uncertainty on the c factor is not added to the data points, as the comparison between data and simulation concentrates on the trend of the fluence faced by the measured pads according to their position in the container volume and because of the strong correlation between the source of the uncertainty on c and the conversion of  $V_{GL}$  ratios into fluence.

The data results exhibit good agreement with the perpendicular orientation simulation both in the absolute value and in the observed trend of the fluence variation inside the tested region of the F19 irradiation channel.

As mentioned above, in the simulation, the active part of each sensor is divided into  $5\times5$  sections, corresponding to the positions of individual pixels (see Fig. 1), and fast neutron flux is calculated for each pixel. Figure 17 compares measured fluences from data and perpendicularly oriented simulation averaged over rows of each column in every sensor. As can be seen, the agreement is good and exhibits a very high sensitivity of measured  $V_{GL}$  to the received fast neutron fluence. It is worth noting that the variations of the



neutron flux inside the reactor core can be sensed with a millimetre spatialresolution.

Figure 17: Comparison of the fluence values as measured by the devices and simulated assuming a perpendicular orientation with respect to the reactor core centre. Single plots refer to single measured (simulated)  $5 \times 5$  sensors. The fluences are shown as a function of the column number, averaged over the 5 rows belonging to the same column, and error bars indicate the standard deviation of the fluence values from pixels in the same column.

### 256 7. Conclusions

The fluence profile on channel F19 at the JSI TRIGA reactor has been measured with LGAD sensors made by an array of  $5 \times 5$  pixel with  $1.3 \text{ mm} \times$ 1.3 mm area. Eight different LGAD sensors taken from the same wafer from the UFSD3 production batch of the FBK foundry have been tested: sensors have been fixed on cross-shaped plastic support at two different depths and inserted on the plastic container used for the irradiation.

The bias at which the gain implant is depleted,  $V_{GL}$ , has been extracted from C-V measurements for each pixel of the tested sensors, before and after the irradiation to  $1.5 \times 10^{15} \,\mathrm{n_{eq}/cm^2}$ . From the ratio of the  $V_{GL}$  values before and after irradiation, the fluence experienced by every pixel has been extracted.

An average fluence of  $1.37 \times 10^{15} \,\mathrm{n_{eq}/cm^2}$  has been measured, 8.7 % lower than the nominal value. A spread in the delivered fluence inside the tested channel has been observed: the difference in fluence around the central value has been quantified between -14.7 % to 15.4 %. The flux of neutrons on the tested region of the reactor core has been simulated using MCNP v.6.1 code with ENDF/B-VII.0 nuclear data libraries and confirms the experimental observations.

The position of the container inside the F19 channel, together with the orientation of the sensor, is unknown. But the experimental results are in good agreement with the simulation of a perpendicular orientation of the sensors to the reactor core.

Only a minor vertical variation of the fluence has been observed, in agreement with the simulation, with a maximum observed spread of  $7.81 \times 10^{13} \, n_{eq}/cm^2$ from the top to the bottom of the tested volume.

The presented study proves a very high sensitivity of the  $V_{GL}$  ratio technique for measurements of neutron flux, and its validity is well confirmed by the good agreement with the simulation. The fine granularity of the LGAD devices and the relatively simple measurement approach offers the possibility of monitoring neutron flux uniformity with millimetre spatial resolution. LGAD sensors demonstrated their effectiveness as precise monitors of the neutron flux inside a reactor core.

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# Appendix A. Sensor assembly modelled isotopic composition and densities

Table A.4: Isotopic composition of the sensor modelled in pure silicon, with density of  $\rho = 2.33 \,\mathrm{g \, cm^{-3}}$ .

	number density
Isotope	$[\times 10^{24} \text{cm}^{-3}]$
$^{28}Si$	$4.6075 \times 10^{-2}$
$^{29}Si$	$2.3406 \times 10^{-3}$
$^{30}Si$	$1.5448 \times 10^{-3}$

Table A.5: Isotopic composition of the capton tape, with density of  $\rho = 1.42 \,\mathrm{g \, cm^{-3}}$ .

	number density
Isotope	$[\times 10^{24} \text{cm}^{-3}]$
$^{1}H$	$5.1250 \times 10^{-2}$
$^{nat}C$	$5.1248 \times 10^{-2}$
$^{14}N$	$8.5102 \times 10^{-3}$
$^{15}N$	$3.1090 \times 10^{-5}$
$^{16}O$	$4.2705 \times 10^{-3}$

Table A.6: Isotopic composition of the FR4 board holder, with density of  $\rho = 1.85 \,\mathrm{g \, cm^{-3}}$ .

1.00 g cm	•
	number density
Isotope	$[\times 10^{24} \text{cm}^{-3}]$
$^{10}B$	$6.3686 \times 10^{-4}$
$^{11}B$	$2.5634 \times 10^{-3}$
$^{16}O$	$3.4641 \times 10^{-2}$
$^{24}Mg$	$2.4018 \times 10^{-3}$
$^{25}Mg$	$3.0406 \times 10^{-4}$
$^{26}Mg$	$3.3477 \times 10^{-4}$
$^{27}Al$	$3.0595 \times 10^{-3}$
$^{28}Si$	$9.2342 \times 10^{-3}$
$^{29}Si$	$4.6910 \times 10^{-4}$
30Si	$3.0960 \times 10^{-4}$
$^{40}Ca$	$2.1185 \times 10^{-3}$
$^{42}Ca$	$1.4139 \times 10^{-5}$
$^{43}Ca$	$2.9503 \times 10^{-6}$
44Ca	$4.5587 \times 10^{-5}$
46Ca	$8.7416 \times 10^{-8}$
48Ca	$4.0867 \times 10^{-6}$